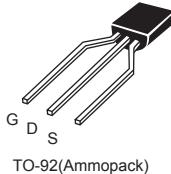
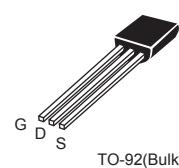


N-Channel Enhancement Mode Field Effect Transistor**FEATURES**

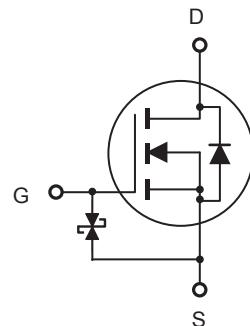
- 650V, 0.35A, $R_{DS(ON)} = 10.5 \Omega$ @ $V_{GS} = 10V$.
- High dense cell design for extremely low $R_{DS(ON)}$.
- Rugged and reliable.
- Lead free product is acquired.
- TO-92(Bulk) & TO-92(Ammopack) package.



TO-92(Ammopack)



TO-92(Bulk)

**ABSOLUTE MAXIMUM RATINGS** $T_A = 25^\circ\text{C}$ unless otherwise noted

| Parameter | Symbol | Limit | Units |
|---------------------------------------|----------------|------------|------------------|
| Drain-Source Voltage | V_{DS} | 650 | V |
| Gate-Source Voltage | V_{GS} | ± 30 | V |
| Drain Current-Continuous | I_D | 0.35 | A |
| Drain Current-Pulsed ^a | I_{DM} | 1.4 | A |
| Maximum Power Dissipation | P_D | 3.1 | W |
| Operating and Store Temperature Range | T_J, T_{stg} | -55 to 150 | $^\circ\text{C}$ |

Thermal Characteristics

| Parameter | Symbol | Limit | Units |
|---|------------------|-------|--------------------|
| Thermal Resistance, Junction-to-Lead ^b | R_{JUL} | 40 | $^\circ\text{C/W}$ |



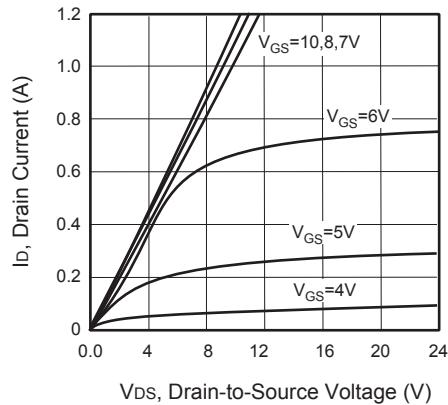
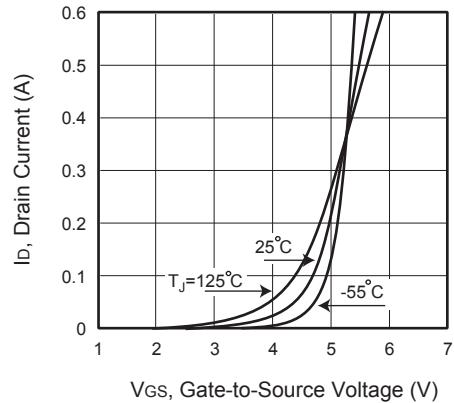
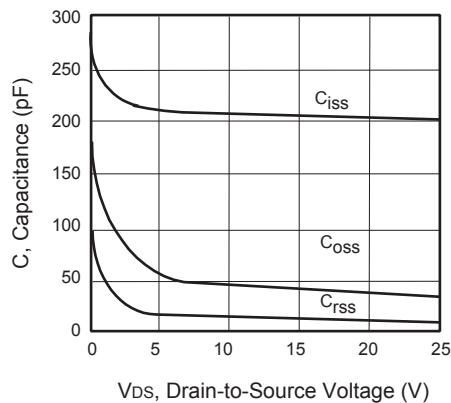
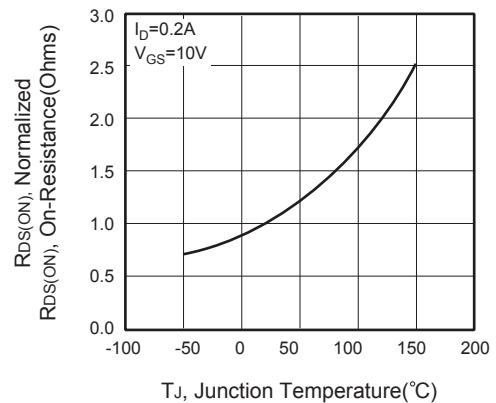
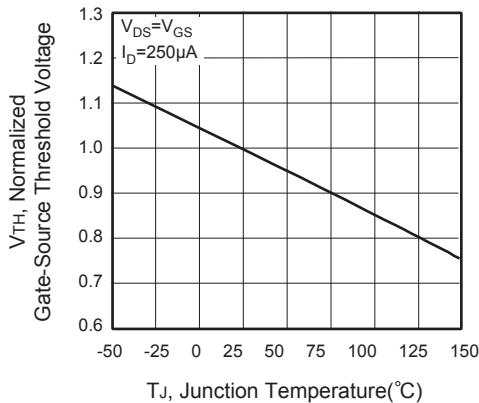
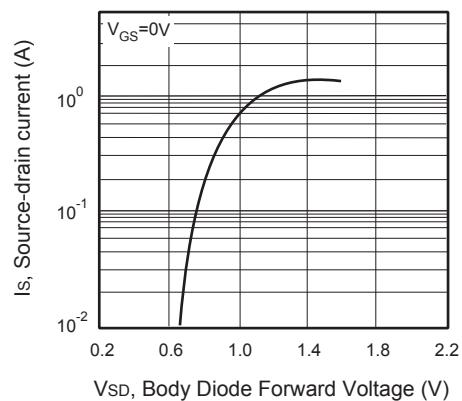
CEK01N65 □

Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

| Parameter | Symbol | Test Condition | Min | Typ | Max | Units |
|---|----------------------------|---|-----|------|------|---------------|
| Off Characteristics | | | | | | |
| Drain-Source Breakdown Voltage | BV_{DSS} | $V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$ | 650 | | | V |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{\text{DS}} = 650\text{V}, V_{\text{GS}} = 0\text{V}$ | | | 25 | μA |
| Gate Body Leakage Current, Forward | I_{GSSF} | $V_{\text{GS}} = 30\text{V}, V_{\text{DS}} = 0\text{V}$ | | | 10 | uA |
| Gate Body Leakage Current, Reverse | I_{GSSR} | $V_{\text{GS}} = -30\text{V}, V_{\text{DS}} = 0\text{V}$ | | | -10 | uA |
| On Characteristics | | | | | | |
| Gate Threshold Voltage | $V_{\text{GS}(\text{th})}$ | $V_{\text{GS}} = V_{\text{DS}}, I_D = 250\mu\text{A}$ | 2.5 | | 4.5 | V |
| Static Drain-Source On-Resistance | $R_{\text{DS}(\text{on})}$ | $V_{\text{GS}} = 10\text{V}, I_D = 0.2\text{A}$ | | 8.5 | 10.5 | Ω |
| Forward Transconductance | g_{FS}^{b} | $V_{\text{DS}} = 10\text{V}, I_D = 0.2\text{A}$ | | 1 | | S |
| Dynamic Characteristics^c | | | | | | |
| Input Capacitance | C_{iss} | $V_{\text{DS}} = 25\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$ | | 210 | | pF |
| Output Capacitance | C_{oss} | | | 45 | | pF |
| Reverse Transfer Capacitance | C_{rss} | | | 20 | | pF |
| Switching Characteristics^c | | | | | | |
| Turn-On Delay Time | $t_{\text{d}(\text{on})}$ | $V_{\text{DD}} = 300\text{V}, I_D = 0.35\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GEN}} = 4.7\Omega$ | | 14.3 | 28.6 | ns |
| Turn-On Rise Time | t_r | | | 14.6 | 29.2 | ns |
| Turn-Off Delay Time | $t_{\text{d}(\text{off})}$ | | | 23 | 46 | ns |
| Turn-Off Fall Time | t_f | | | 16 | 32 | ns |
| Total Gate Charge | Q_g | $V_{\text{DS}} = 480\text{V}, I_D = 0.35\text{A}, V_{\text{GS}} = 10\text{V}$ | | 5.8 | 7.7 | nC |
| Gate-Source Charge | Q_{gs} | | | 2 | | nC |
| Gate-Drain Charge | Q_{gd} | | | 2.3 | | nC |
| Drain-Source Diode Characteristics and Maximum Ratings | | | | | | |
| Drain-Source Diode Forward Current | I_S | | | | 0.35 | A |
| Drain-Source Diode Forward Voltage ^b | V_{SD} | $V_{\text{GS}} = 0\text{V}, I_S = 0.2\text{A}$ | | | 1.5 | V |

Notes :

- a.Repetitive Rating : Pulse width limited by maximum junction temperature.
 b.Pulse Test : Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.
 c.Guaranteed by design, not subject to production testing.□

**Figure 1. Output Characteristics****Figure 2. Transfer Characteristics****Figure 3. Capacitance****Figure 4. On-Resistance Variation with Temperature****Figure 5. Gate Threshold Variation with Temperature****Figure 6. Body Diode Forward Voltage Variation with Source Current**

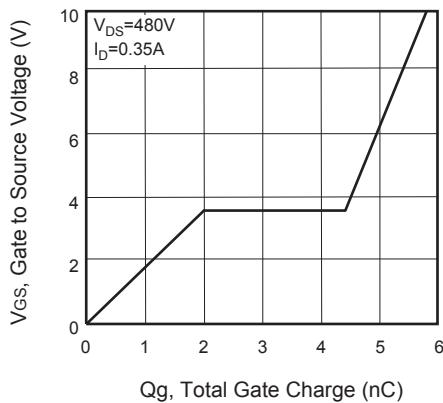


Figure 7. Gate Charge

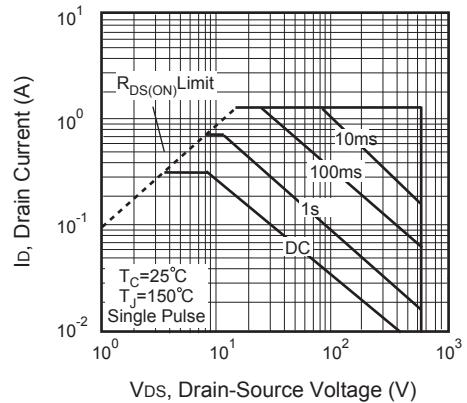


Figure 8. Maximum Safe Operating Area

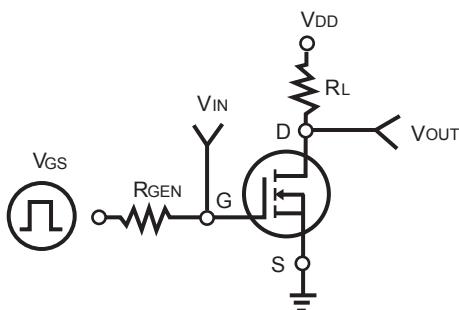


Figure 9. Switching Test Circuit

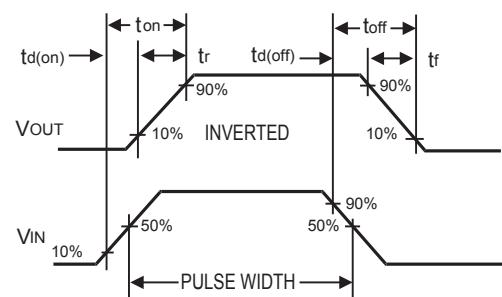


Figure 10. Switching Waveforms

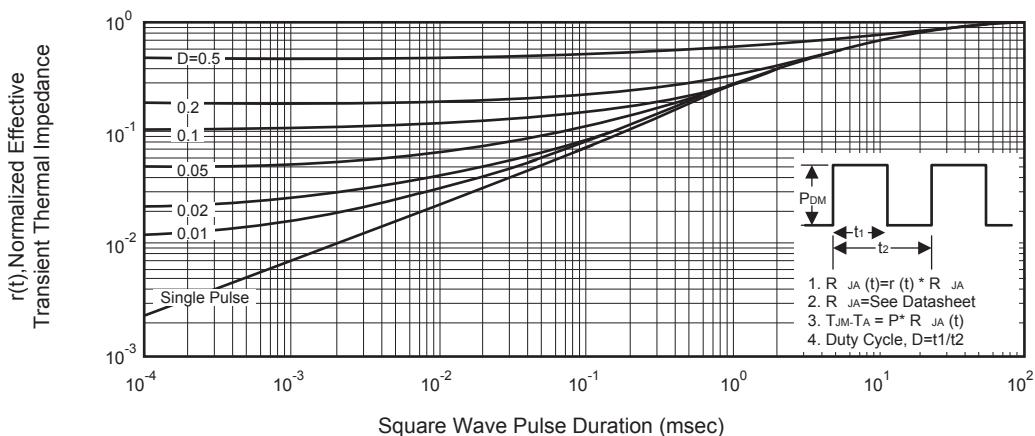


Figure 11. Normalized Thermal Transient Impedance Curve